



Form PTO 1449 (Modified)		- U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 215544US2			SERIAL NO.  NEW APPLICATION	
LIST OF	REFE	RENGES CITED BY APPI	LICANT	APPLICANT Takuji MATSUMOT			ΓO, et al.	
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				U.S. PATENT D	OCUMENTS			872 09/ 11/
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		DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION YES NO		
	AO	8-228145 -	3/9/96	<b>.</b>	Japan (with Partial English Translation)			X
A.s.	AP	2000-243973	9/8/00	Japan (Corresponding to US Application No. 09/466,934)			X	
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		OTUED DEC	EDENCES (	Industrian Author	Title Date Porting	Page 6	<u> </u>	
4	OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  S. MAEDA, et al. Impact of 0.18um SOI CMOS Technology using Hybrid Trench Isolation with High Resistivity Substrate on Embedded RF/Analog Applications, 2000 Symposium on VLSI Technology Digest of Technical Papers, pp. 154-155							
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*Examiner: Ini	tial if re	eference s considered, what considered, Include copy	hether or not	citation is in con	iformance with MPEP	609; Draw li	ne through	citation if not in